

**Search Notes**

Application/Control No.

10/796,194

Examiner

Ren L. Yan

Applicant(s)/Patent under  
Reexamination

SATOH ET AL.

Art Unit

2854

**SEARCHED**

| Class | Subclass       | Date | Examiner |
|-------|----------------|------|----------|
| 101   | 116            |      |          |
|       | 117            |      |          |
|       | 118            |      |          |
|       | 232            |      |          |
| 271   | 10.01          |      |          |
|       | 10.03          |      |          |
|       | 110            |      |          |
|       | 111            |      |          |
|       | 258.01         |      |          |
|       | 259            |      |          |
|       | 265.01         |      |          |
|       | 265.02         |      |          |
| above | search 3/22/07 | RY   |          |
|       | updated        |      |          |
|       |                |      |          |
|       |                |      |          |
|       |                |      |          |

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE | EXMR |
|--|------|------|
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |
|  |      |      |

**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |